

K2845-VB Datasheet

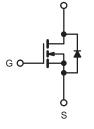
N-Channel 900 V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	900)			
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	2.7			
Q _g (Max.) (nC)	200)			
Q _{gs} (nC)	24				
Q _{gd} (nC)	110)			
Configuration	Sing	Single			

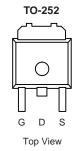
FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET



ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	LIMIT	UNIT			
Drain-Source Voltage	V_{DS}	900	V			
Gate-Source Voltage	V_{GS}	± 20				
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 ^{\circ}\text{C}$	I _D	2.0			
Continuous Drain Current	V_{GS} at 10 $V_{C} = 100 ^{\circ}C$		1.5	Α		
Pulsed Drain Current ^a	I _{DM}	8.0				
Linear Derating Factor		1.5	W/°C			
Single Pulse Avalanche Energy ^b	E _{AS}	470	mJ			
Repetitive Avalanche Currenta	I _{AR}	4.8	A			
Repetitive Avalanche Energy ^a	E _{AR}	19	mJ			
Maximum Power Dissipation	aximum Power Dissipation $T_C = 25 ^{\circ}C$		120	W		
Peak Diode Recovery dV/dt ^c	dV/dt	2.0	V/ns			
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	- 55 to + 150	°C			
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	7		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in		
	0-32 OF IVIS SCIEW		1.1	N⋅m		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=23~mH, $R_g=25~\Omega$, $I_{AS}=7.8~A$ (see fig. 12). c. $I_{SD}\leq7.8~A$, $dI/dt\leq140~A/\mu s$, $V_{DD}\leq600~V$, $T_J\leq150~^{\circ}C$. d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	40			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65			

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D = 250 μA	900	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 800 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	100 500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}		I _D = 1.7 A ^b	_	2.7	-	Ω
Forward Transconductance	9fs		= 100 V, I _D = 1.7 A ^b	5.6	-	-	S
Dynamic	<u> </u>		_	L		1	
Input Capacitance	C _{iss}	V 0V		-	1800	-	
Output Capacitance	C _{oss}	1	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$	-	500	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	-	290	-	
Total Gate Charge	Qg			-	-	200	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 1.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	24	nC
Gate-Drain Charge	Q_{gd}	. See lig. 0 and 13		-	-	110	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 400 V, I_{D} = 1.8 A, R_{g} = 6.2 Ω , R_{D} = 52 Ω see fig. 10 ^b		-	19	-	- ns
Rise Time	t _r			-	38	-	
Turn-Off Delay Time	$t_{d(off)}$			-	120	-	
Fall Time	t _f			-	39	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	- N.I.
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 1.8 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 1.8 A, dl/dt = 100 A/μs ^b		-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

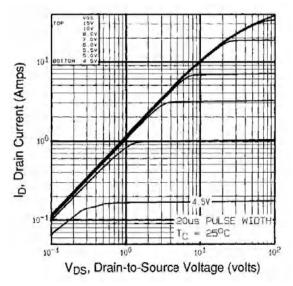


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

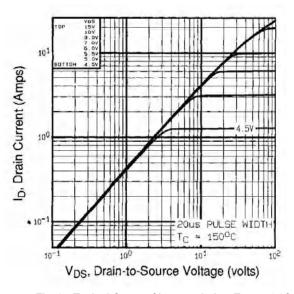


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

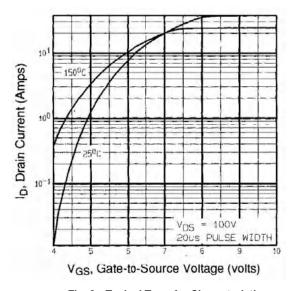


Fig. 3 - Typical Transfer Characteristics

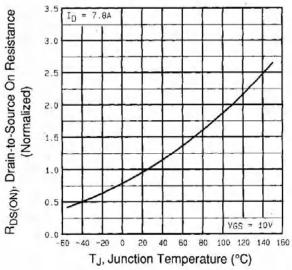


Fig. 4 - Normalized On-Resistance vs. Temperature



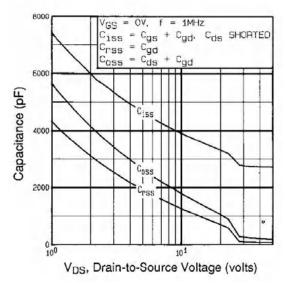


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

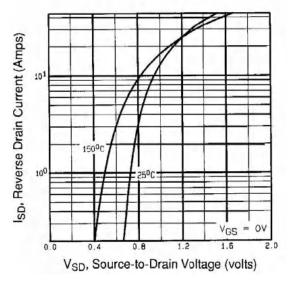


Fig. 7 - Typical Source-Drain Diode Forward Voltage

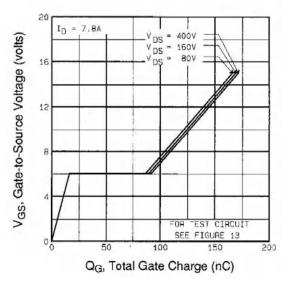


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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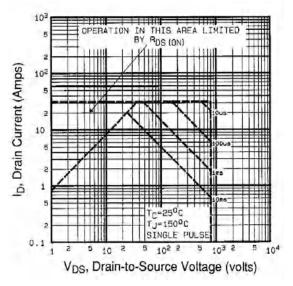


Fig. 8 - Maximum Safe Operating Area



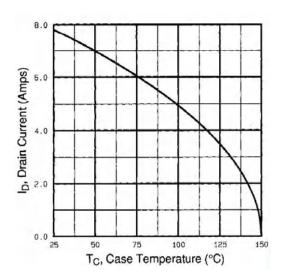


Fig. 9 - Maximum Drain Current vs. Case Temperature

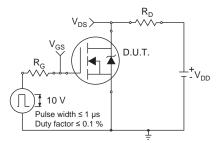


Fig. 10a - Switching Time Test Circuit

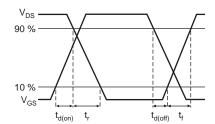


Fig. 10b - Switching Time Waveforms

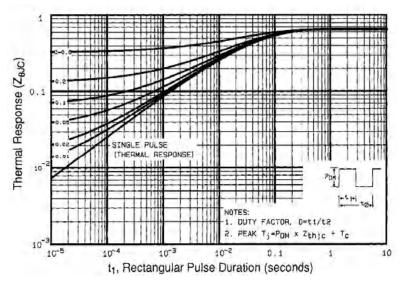


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



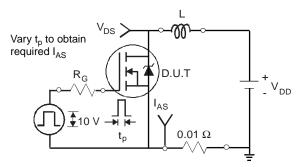


Fig. 12a - Unclamped Inductive Test Circuit

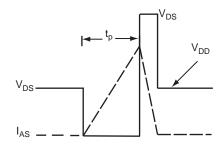


Fig. 12b - Unclamped Inductive Waveforms

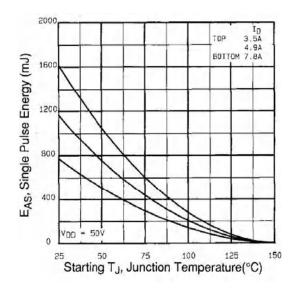


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

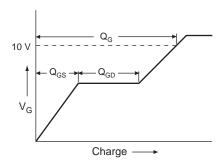


Fig. 13a - Basic Gate Charge Waveform

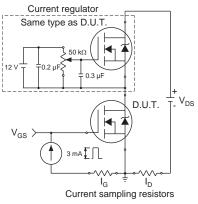
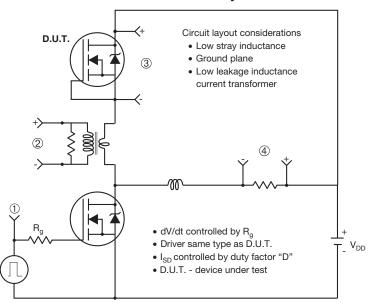


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit



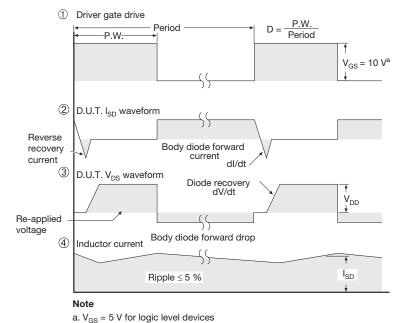
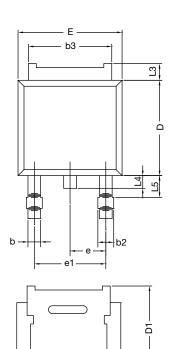
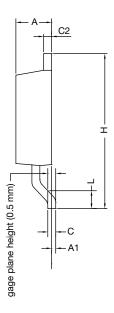


Fig. 14 - For N-Channel



TO-252AA CASE OUTLINE





	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	2.18	2.38	0.086	0.094	
A1	-	0.127	ı	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	-	0.205	-	
E	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	=	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347					

Note

• Dimension L3 is for reference only.



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